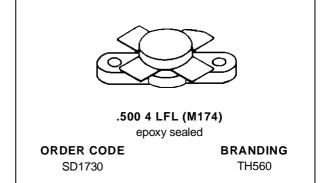
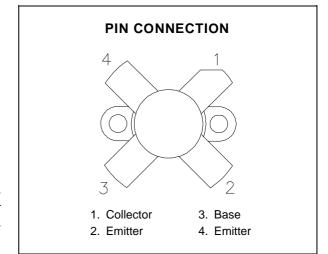


SD1730 (TH560)

RF & MICROWAVE TRANSISTORS HF SSB APPLICATIONS

- OPTIMIZED FOR SSB
- 30 MHz
- 28 VOLTS
- IMD -30dB
- EFFICIENCY 40%
- **COMMON EMITTER**
- GOLD METALLIZATION
- P_{OUT} = 220 W PEP WITH 12 dB GAIN





DESCRIPTION

The SD1730 is a 28 V epitaxial silicon NPN planar transistor designed primarily for SSB and VHF communications. The devices utilizes emitter ballasting for improved ruggedness and reliability.

ABSOLUTE MAXIMUM RATINGS $(T_{case} = 25^{\circ}C)$

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	70	V
V _{CEO}	Collector-Emitter Voltage	35	V
V_{EBO}	V _{EBO} Emitter-Base Voltage		V
lc	I _C Device Current		А
P _{DISS}	Power Dissipation	320	W
TJ	Junction Temperature	+200	°C
T _{STG}	Storage Temperature	- 65 to +150	°C

THERMAL DATA

R _{TH(j-c)}	Junction-Case Thermal Resistance	0.6	°C/W

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ELECTRICAL SPECIFICATIONS (T_{case} = 25°C)

STATIC

Symbol	Test Conditions		Value			
Symbol	rest conditions		Min.	Тур.	Max.	Unit
BVces	I _C = 100 mA	$V_{BE} = 0 V$	70	_	_	V
BVCEO	I _C = 200 mA	$I_B = 0 \text{ mA}$	35	_	_	V
BV _{EBO}	I _E = 20 mA	$I_C = 0 \text{ mA}$	4.0	_	_	V
ICEO	V _{CE} = 30 V	$I_E = 0 \text{ mA}$	_	_	5	mA
ICES	V _{CE} = 35 V	$I_E = 0 \text{ mA}$		_	5	mA
hFE	Vce = 5 V	I _C = 7 A	15	_	60	_

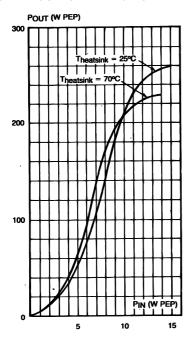
DYNAMIC

Cumbal	Test Conditions			Value			Unit
Symbol	yiiboi rest Conditions				Тур.	Max.	Unit
Роит	f = 30 MHz	$V_{CE} = 28 \text{ V}$	$I_{CQ} = 750 \text{ mA}$	220	_	_	W
Pg*	P _{OUT} = 220 W PEP	$V_{CE} = 28 \text{ V}$	$I_{CQ} = 750 \text{ mA}$	12	_	_	dB
IMD*	P _{OUT} = 220 W PEP	V _{CE} = 28 V	I _{CQ} = 750 mA	_		-30	dBc
η _C *	P _{OUT} = 220 W PEP	$V_{CE} = 28 \text{ V}$	$I_{CQ} = 750 \text{ mA}$	40	_	_	%
Сов	f = 1 MHz	V _{CB} = 28 V		_	450	_	pF
Load Mismatch	P _{OUT} = 220 W PEP	V _{CE} = 28 V	$I_{CQ} = 750 \text{ mA}$	_	∞:1	_	VSWR

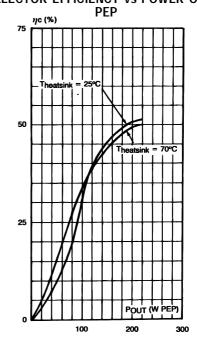
Note: $f_1 = 30.00 \text{ MHz}, f_2 = 30.001 \text{ MHz}$

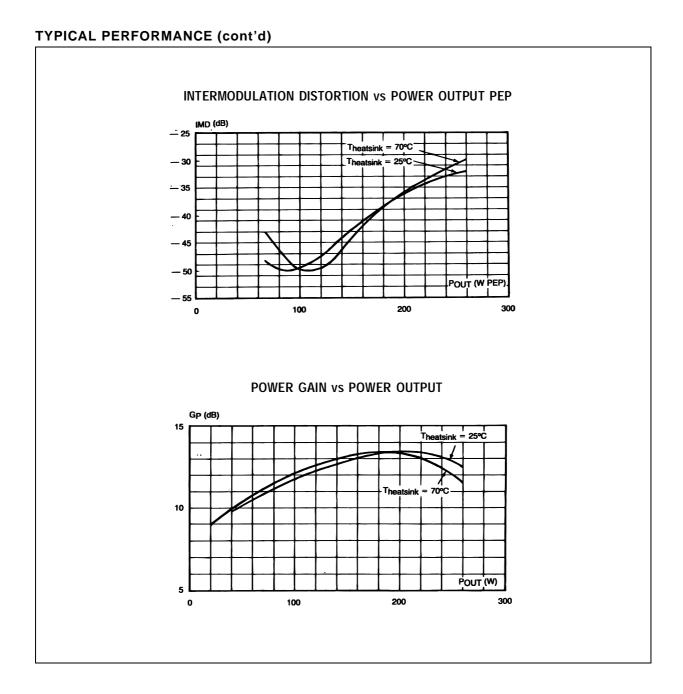
TYPICAL PERFORMANCE

POWER OUTPUT PEP vs POWER INPUT



COLLECTOR EFFICIENCY vs POWER OUTPUT

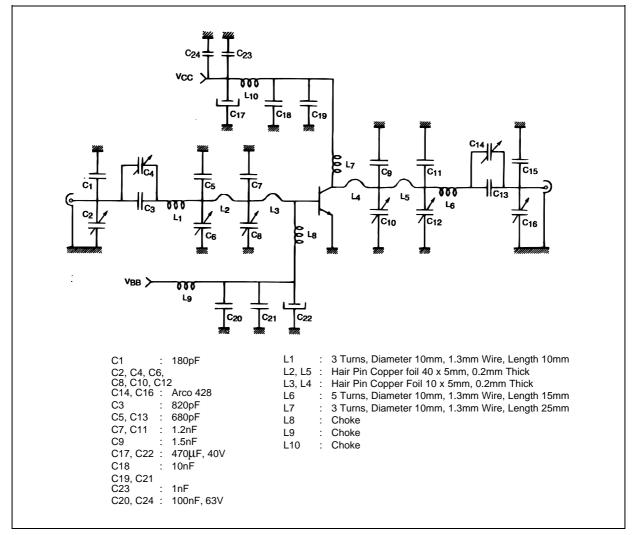


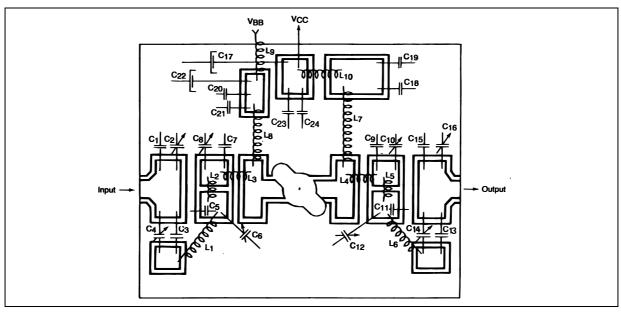


IMPEDANCE DATA

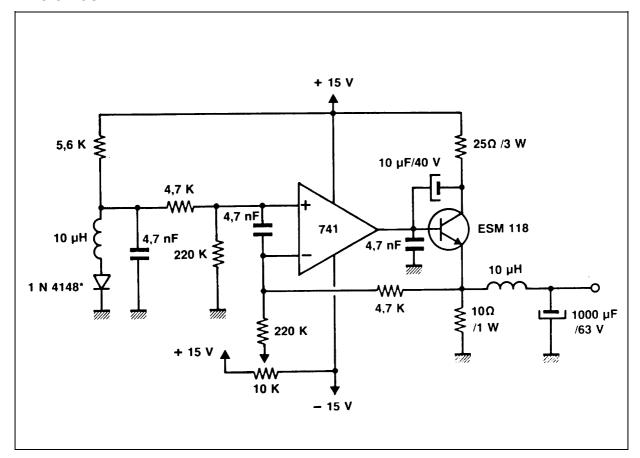
FREQ.	Z _{IN} (Ω)	Z _{CL} (Ω)
30 MHz	1.15 + j 0.41	1.25 + j 1.92

TEST CIRCUIT

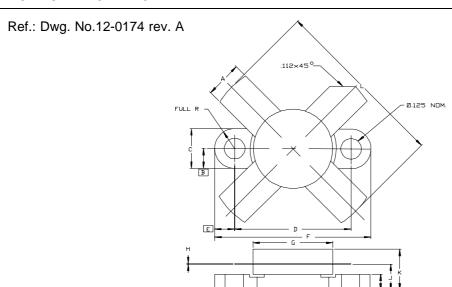




BIAS CIRCUIT



PACKAGE MECHANICAL DATA



SGS-THOMSON MICROELECTRONICS				CONT'D			
	MINIMUM Inches/mm	MAXIMUM Inches/mm		MINIMUM Inches/mm	MAXIMUM Inches/mm		
Α	.220/5,59	.230/5,84	К		.280/7,11		
В	.125/3,18		L		1.050/26,67		
С	.245/6,22	.255/6,48					
D	.720/18,28	.730/18,54					
E	.125/3,18						
F	.970/24,64	.980/24,89					
G	.495/12,57	.505/12,83					
Н	.003/0,08	.007/0,18					
I	.090/2,29	.110/2,79					
J	.160/4,06	.175/4,45					

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